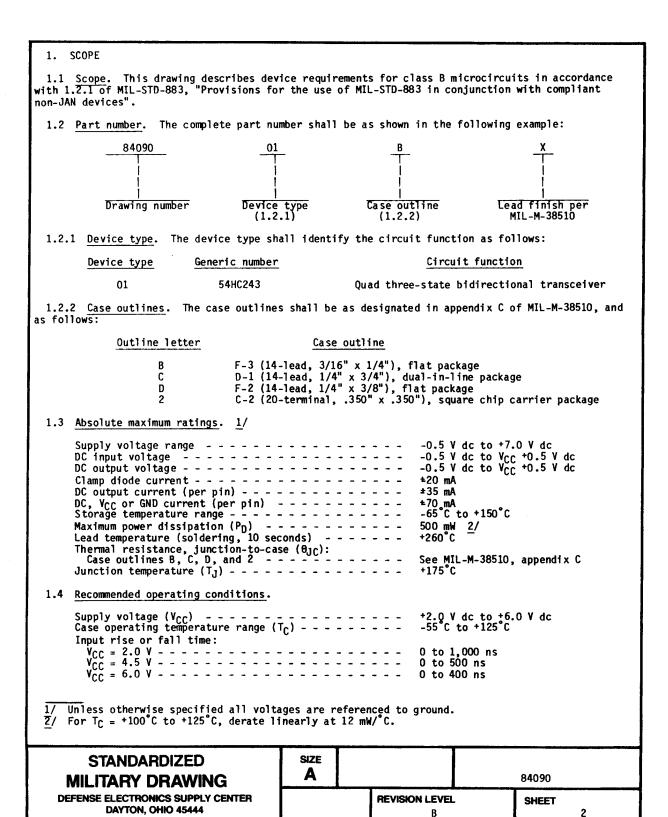
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В	27014	to ca	se Edi	2.	y drawing format. Added vendor CAGE no. Clarification in table I, with a change on al changes throughout. Change code ident.								, fing	K											
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AND	AGENCIE	S OF T	HΕ	1	1	0c1	tobe	r 19			·		╀	A 14933				84090							
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# 2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

**SPECIFICATION** 

**MILITARY** 

MIL-M-38510

- Microcircuits, General Specification for.

**STANDARD** 

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

## 3. REQUIREMENTS

- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
  - 3.2.1 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 1.
  - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
  - 3.2.3 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

STANDARDIZED MILITARY DRAWING	SIZE A		84090
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL B	SHEET 3

Test	Symbol		0 	ondition	ns 1/ +125 C	Group A		mits	Unii
	<u>i</u>	<u> </u>	inless o	therwise	+125°C specified		Min	Max	<u> </u>
High level output voltage	VOH	VIN = V	IH or V	IL	V <sub>CC</sub> = 2.0 V	i i 1, 2, 3	1.9		i v
<b>y</b> -	İ	i 1-01 =	-υ μ.,		$V_{CC} = 4.5 \text{ V}$	_	4.4	<del>           </del>	
	İ	j			$V_{CC} = 6.0 \text{ V}$	- <u>i</u>	5.9	<del> </del>	İ
	İ	1101 <	6.0 mA		V <sub>CC</sub> = 4.5 V	-	3.7		į
	 	I <sub>0</sub>   <	7.8 mA		V <sub>CC</sub> = 6.0 V	- <u>i</u> 	5.2	i	j I
Low level output	V <sub>OL</sub>	AIN = A	IH or V	IL	V <sub>CC</sub> = 2.0 V			0.1	
voltage	ļ	1101 <	VIN = VIH or VIL  IO  < 20 μA		V <sub>CC</sub> = 4.5 V	1, 2, 3		0.1	V 
	ļ	<u> </u> 			$V_{CC} = 6.0 \text{ V}$	-		0.1	
		1101 <	6.0 mA		V <sub>CC</sub> = 4.5 V	-	_	0.4	
		1101 ₹	7.8 mA		V <sub>CC</sub> = 6.0 V	-		0.4	
High level input	Λ <sup>IH</sup>				V <sub>CC</sub> = 2.0 V		1.5		
voltage <u>2</u> /		<b>[</b>			V <sub>CC</sub> = 4.5 V	_  1, 2, 3    -	3.15	! 	<b>V</b>
		   			V <sub>CC</sub> = 6.0 V	-	4.2		
Low level input	VIL				V <sub>CC</sub> = 2.0 V	<u> </u>		0.3	
voltage <u>2</u> /	-	i 			V <sub>CC</sub> = 4.5 V	1, 2, 3		   0.9	٧
					$V_{CC} = 6.0 \text{ V}$	_]		1.2	
Output capacitance	COUT	V <sub>OUT</sub> = See 4.3	0 V .1c	T <sub>C</sub> = +	25°C	4		20	pF
Input capacitance	CIN	V <sub>IN</sub> = 0 See 4.3	٧	T <sub>C</sub> = +	25°C	4		10 l	pF
Quiescent current	Icc	V <sub>CC</sub> = 6	.0 V	AIN =	V <sub>CC</sub> or GND	1, 2, 3	 	160	μА
Input leakage current	IIN	V <sub>CC</sub> = 6	.0 <b>V</b>	A <sup>IN</sup> =	V <sub>CC</sub> or GND	1, 2, 3	]	<b>±</b> 1	μА
Off-state output current	Ioz	Output (	enables VCC or G	= VIH O	r V <sub>IL</sub>	1, 2, 3		±10	μА
See footnotes at end of	table.				· · · · · · · · · · · · · · · · · · ·				
STANDARD			SIZE						
MILITARY DR DEFENSE ELECTRONICS			Α			84	090		

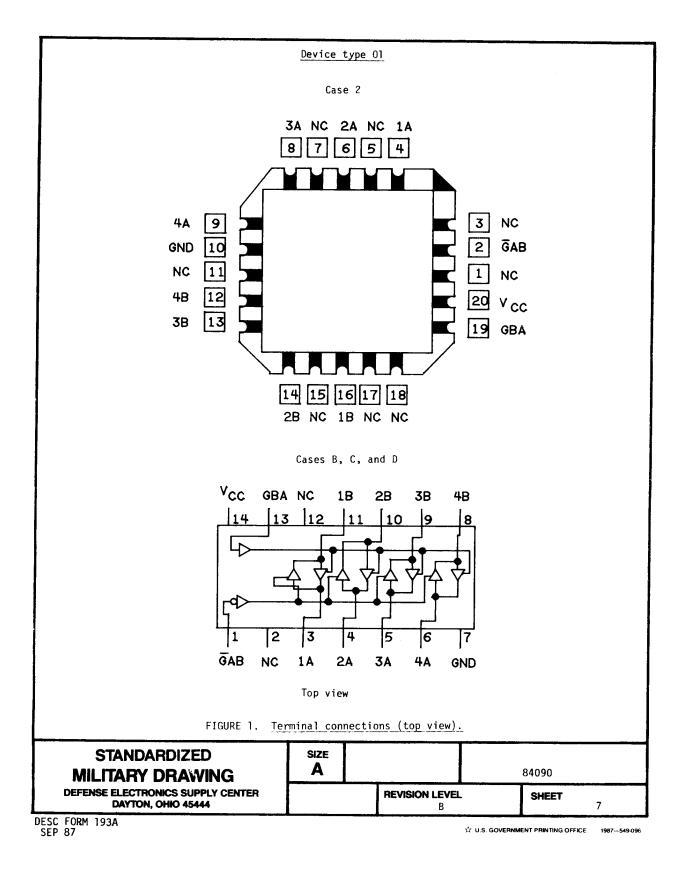
Test	Symbol	Conditio	Group A	Limits		Unit	
		Conditio -55°C < T <sub>C</sub> < unless otherwis	subgroups	Min	Max		
Functional tests		See 4.3.1d		7		!   	   
Propagation delay	t <sub>PHL</sub> ,	T <sub>C</sub> = +25°C	V <sub>CC</sub> = 2.0 V	9		110	ns
<u>3</u> /	tpLH	C <sub>L</sub> = 50 pF ±10%	$V_{CC} = 4.5 \text{ V}$	-		22	!   
		See figure 3	V <sub>CC</sub> = 6.0 V	-i i		19	
		T <sub>C</sub> = -55°C, +125°C	V <sub>CC</sub> = 2.0 V	10, 11		165	ns
		C <sub>L</sub> = 50 pF ±10%	$V_{CC} = 4.5 \text{ V}$	_		33	
		See figure 3	$V_{CC} = 6.0 \text{ V}$	-		28	
Output enable time	t <sub>PZH</sub> ,	T <sub>C</sub> = +25°C	V <sub>CC</sub> = 2.0 V	9		175	ns
to active output $\frac{3}{2}$	tpZL	C <sub>L</sub> = 50 pF ±10%	$V_{CC} = 4.5 \text{ V}$	-		35	
		$R_L = 1 k\Omega$   See figure 3	$V_{CC} = 6.0 \text{ V}$	   		30	
		T <sub>C</sub> = -55°C, +125°C	V <sub>CC</sub> = 2.0 V	10, 11		265	ns
	ļ !	C <sub>L</sub> = 50 pF ±10%	V <sub>CC</sub> = 4.5 V	-		53	
		R <sub>L</sub> = 1 kΩ   See figure 3	V <sub>CC</sub> = 6.0 V	-¦		45	
Output disable time	lt <sub>PHZ</sub> ,	T <sub>C</sub> = +25°C	V <sub>CC</sub> = 2.0 V	9	<u> </u>	200	ns
from active output $3/$	tPLZ	C <sub>L</sub> = 50 pF ±10%	V <sub>CC</sub> = 4.5 V	-		40	
		R <sub>L</sub> = 1 kΩ See figure 3	V <sub>CC</sub> = 6.0 V	-  	<del> </del>	34	
		T <sub>C</sub> = -55°C, +125°C	V <sub>CC</sub> = 2.0 V	10, 11	1	300	ns
		C <sub>L</sub> = 50 pF ±10%	V <sub>CC</sub> = 4.5 V	-		60	
	1	   R <sub>L</sub> = 1 kΩ   See figure 3	V <sub>CC</sub> = 6.0 V	<u>-</u>	<del> </del>	<del>- 51</del>	
ee footnotes at end o	f table.	I	1	11	]	<b>_</b>	

STANDARDIZED MILITARY DRAWING	SIZE A		84090
DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		REVISION LEVEL B	SHEET 5

Test	Symbol	Condition 55°C (To	Conditions 1/ -55°C < T <sub>C</sub> < +125°C				Unit
		unless otherwis	e specified	subgroups	Min	Max	<u> </u>
Transition time $\frac{4}{}$	t <sub>THL</sub> ,	T <sub>C</sub> = +25°C	V <sub>CC</sub> = 2.0 V	9		60	ns
	tTLH	C <sub>L</sub> = 50 pF ±10%	$V_{CC} = 4.5 \text{ V}$	-		12	! !
	; [	   See figure 3	$V_{CC} = 6.0 \text{ V}$			10	] ] 
	1	T <sub>C</sub> = -55°C, +125°C	V <sub>CC</sub> = 2.0 V	10, 11		90	ns
		CL = 50 pF ±10%	V <sub>CC</sub> = 4.5 V	-		18	 
		!   See figure 3	V <sub>CC</sub> = 6.0 V	 		15	İ

- For a power supply of 5 V ±10%, the worst case output voltages (V<sub>OH</sub> and V<sub>OL</sub> occur for HC at 4.5 V. Thus, the 4.5 V values should be used when designing with this supply. Worst case V<sub>IH</sub> and V<sub>IL</sub> occur at V<sub>CC</sub> = 5.5 V and 4.5 V, respectively. (The V<sub>IH</sub> value at 5.5 V is 3.85 V.) The worst case leakage current (I<sub>IN</sub>, I<sub>CC</sub>, and I<sub>OZ</sub>) occur for CMOS at the higher voltage and so the 6.0 V values should be used. Power dissipation capacitance (C<sub>PD</sub>), typically 50 pF, determines the no load dynamic power consumption, P<sub>D</sub> = C<sub>PD</sub> V<sub>CC</sub>2f<sup>+</sup>I<sub>CC</sub> V<sub>CC</sub>, and the no load dynamic current consumption, I<sub>S</sub> = C<sub>PD</sub> V<sub>CC</sub> f<sup>+</sup>I<sub>CC</sub>.
- $\underline{2}$ / Testing not required if applied as forcing function for  $V_{OH}$  or  $V_{OL}$ .
- $\frac{3}{}$  Propagation delay times, when  $V_{CC}$  = 2.0 V and 6.0 V, if not tested shall be guaranteed to the specified parameters.
- $\frac{4}{}$  Transition time (t<sub>TLH</sub>, t<sub>THL</sub>), if not tested, shall be guaranteed to the specified parameters.
- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 <u>Verification and review.</u> DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		RE	VISION LEVEL B	SHEET	6

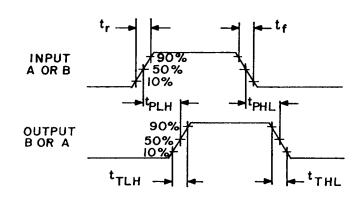


Contr	ol inputs	Data port status					
GAB	GBA	Α	В				
H	Н	Output	Input				
L	H	Isolated	Isolated				
Н	] L	Isolated	Isolated				
L	L	Input	Output				

FIGURE 2. Truth table.

# STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 SIZE A 84090 REVISION LEVEL B SHEET 8

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 $t_r$  and  $t_f \le 6$  ns

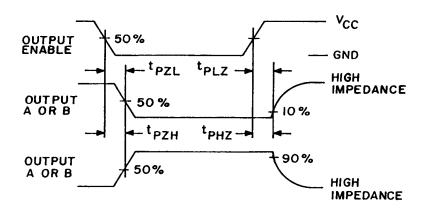


FIGURE 3. Switching waveform.

# STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444 SIZE A 84090 REVISION LEVEL B SHEET 9

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- 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
  - a. Burn-in test (method 1015 of MIL-STD-883).
    - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
    - (2)  $T_A = +125^{\circ}C$ , minimum.
  - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method  $\frac{5005}{5005}$  of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
  - 4.3.1 Group A inspection.
    - a. Tests shall be as specified in table II herein.
    - b. Subgroups 5, 6, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
    - c. Subgroup 4 ( $C_{\mbox{IN}}$  and  $C_{\mbox{OUT}}$  measurement) shall be measured only for the initial test and after process or design changes which may affect input capacitance.
    - d. Subgroup 7 test sufficient to verify the truth table.
  - 4.3.2 Groups C and D inspections.
    - a. End-point electrical parameters shall be as specified in table II herein.
    - b. Steady-state life test (method 1005 of MIL-STD-883) conditions:
      - Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
      - (2)  $T_A = +125^{\circ}C$ , minimum.
      - (3) Test duration: 1,000 hours, except as permitted by appendix B of MIL-M-38510 and method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	
Final electrical test parameters (method 5004)	1*, 2, 9
Group A test requirements (method 5005)	1, 2, 3, 4, 7, 9, 10, 11**
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

PDA applies to subgroup 1.
\* Subgroups 10 and 11, if not tested shall be guaranteed to the specified limits in table I.

# 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

## 6. NOTES

- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
  - 6.2 Replaceability. Replaceability is determined as follows:
    - a. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
    - When a QPL source is established, the part numbered device specified in this drawing will be replaced by the microcircuit identified as part number M38510/65502B---.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

## **STANDARDIZED** SIZE Α **MILITARY DRAWING** DEFENSE ELECTRONICS SUPPLY CENTER

DAYTON, OHIO 45444

6.4 Approved sources of supply. Approved sources of supply are listed herein. Additional sources will be added as they become available. The vendors listed herein have agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

   Military drawing   part number	Vendor   CAGE   number	Vendor similar part number <u>1</u> /	Replacement military specification part number
8409001BX	01295	ISNJ54HC243WA	M38510/65502BBX
8409001CX	01295 04713 18714 27014	  SNJ54HC243J  54HC243/BCAJC  CD54HC243F/3A  MM54HC243J/883J	M38510/65502BCX
8409001DX	01295	SNJ54HC243W	M38510/65502BDX
84090012X	04713	  54HC243M/B2CJC  MM54HC243E/883	M38510/65502B2X

 $\frac{1}{}$  Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number	Vendor name and address
01295	Texas Instruments, Inc. P.O. Box 6448 Midland, TX 79701
04713	Motorola, Inc. 7402 S. Price Rd. Tempe, AZ 85283
18714	RCA Corporation Solid State Division Route 202 Somerville, NJ 08876
27014	National Semiconductor P.O. Box 58090 Santa Clara, CA 95052-8090

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